

Search Notes

Application/Control No.

10/526,150

Examiner

Chau N. Nguyen

Applicant(s)/Patent under
Reexamination

WEYL ET AL.

Art Unit

2831

SEARCHED

Class	Subclass	Date	Examiner
174	28	6/7/2007	CN
	111		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR